

## N and P Channel Enhancement Mode Power MOSFET

### Description

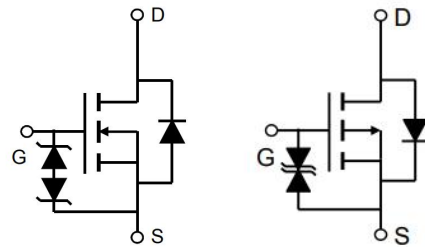
The G1NP02LLE uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge. It can be used in a wide variety of applications.

### General Features

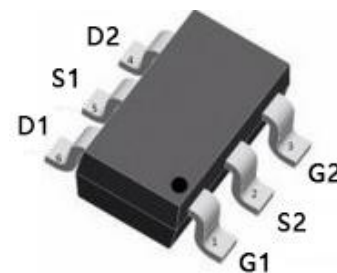
- NMOS
- $V_{DS}$  20V
- $I_D$  (at  $V_{GS} = 10V$ ) 1.3A
- $R_{DS(ON)}$  (at  $V_{GS} = 4.5V$ ) < 210m $\Omega$
- $R_{DS(ON)}$  (at  $V_{GS} = 2.5V$ ) < 270m $\Omega$
- $R_{DS(ON)}$  (at  $V_{GS} = 1.8V$ ) < 360m $\Omega$
- 100% Avalanche Tested
- RoHS Compliant
- ESD (HBM)>2.0KV
  
- PMOS
- $V_{DS}$  -20V
- $I_D$  (at  $V_{GS} = -10V$ ) -1.1A
- $R_{DS(ON)}$  (at  $V_{GS} = -4.5V$ ) < 460m $\Omega$
- $R_{DS(ON)}$  (at  $V_{GS} = -2.5V$ ) < 580m $\Omega$
- $R_{DS(ON)}$  (at  $V_{GS} = -1.8V$ ) < 760m $\Omega$
- 100% Avalanche Tested
- RoHS Compliant
- ESD (HBM)>2.0KV

### Application

- Power switch
- DC/DC converters



Schematic diagram



SOT-23-6L

### Ordering Information

Device	Package	Marking	Packaging
G1NP02LLE	SOT-23-6L	G1NP02E	3000pcs/Reel

### Absolute Maximum Ratings $T_C = 25^\circ C$ , unless otherwise noted

Parameter	Symbol	NMOS	PMOS	Unit
Drain-Source Voltage	$V_{DS}$	20	-20	V
Continuous Drain Current	$I_D$	1.3	1.1	A
Pulsed Drain Current (note1)	$I_{DM}$	5.2	4.4	A
Gate-Source Voltage	$V_{GS}$	$\pm 10$	$\pm 10$	V
Power Dissipation	$P_D$	1.25	1.25	W
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	-55 To 150	-55 To 150	$^\circ C$

### Thermal Resistance

Parameter	Symbol	NMOS	PMOS	Unit
Thermal Resistance, Junction-to-Ambient	$R_{thJA}$	100	100	$^\circ C/W$

NMOS Specifications $T_J = 25^\circ\text{C}$ , unless otherwise noted						
Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
<b>Static Parameters</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	20	--	--	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 20V, V_{GS} = 0V$	--	--	1	$\mu A$
Gate-Source Leakage	$I_{GSS}$	$V_{GS} = \pm 10V$	--	--	$\pm 10$	$\mu A$
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	0.35	0.55	1	V
Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 4.5V, I_D = 0.65A$	--	170	210	m $\Omega$
		$V_{GS} = 2.5V, I_D = 0.55A$	--	220	270	
		$V_{GS} = 1.8V, I_D = 0.45A$	--	300	360	
Forward Transconductance	$g_{FS}$	$V_{GS} = 5V, I_D = 0.55A$	--	1.3	--	S
<b>Dynamic Parameters</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V,$ $V_{DS} = 10V,$ $f = 1.0MHz$	--	146	--	pF
Output Capacitance	$C_{oss}$		--	108	--	
Reverse Transfer Capacitance	$C_{rss}$		--	52	--	
Total Gate Charge	$Q_g$	$V_{DD} = 10V,$ $I_D = 0.65A,$ $V_{GS} = 4.5V$	--	1	--	nC
Gate-Source Charge	$Q_{gs}$		--	0.27	--	
Gate-Drain Charge	$Q_{gd}$		--	0.21	--	
Turn-on Delay Time	$t_{d(on)}$	$V_{DD} = 10V,$ $I_D = 0.65A,$ $R_G = 10\Omega$	--	17.5	--	ns
Turn-on Rise Time	$t_r$		--	2.1	--	
Turn-off Delay Time	$t_{d(off)}$		--	9.5	--	
Turn-off Fall Time	$t_f$		--	22	--	
<b>Drain-Source Body Diode Characteristics</b>						
Continuous Body Diode Current	$I_S$	$T_C = 25^\circ\text{C}$	--	--	1.3	A
Body Diode Voltage	$V_{SD}$	$T_J = 25^\circ\text{C}, I_{SD} = 0.65A, V_{GS} = 0V$	--	--	1.2	V
Reverse Recovery Charge	$Q_{rr}$	$I_F = 0.65A, V_{GS} = 0V$ $di/dt = 20A/\mu s$	--	0.39	--	nC
Reverse Recovery Time	$T_{rr}$		--	14	--	ns

### Notes

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. Identical low side and high side switch with identical  $R_G$

### Gate Charge Test Circuit



### Switch Time Test Circuit

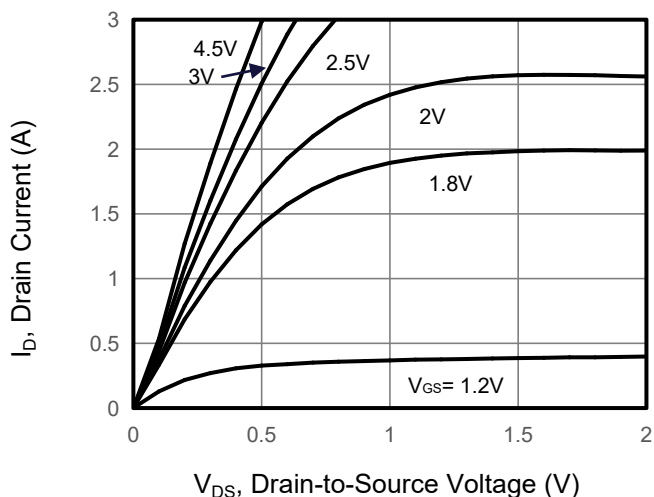


### EAS Test Circuit

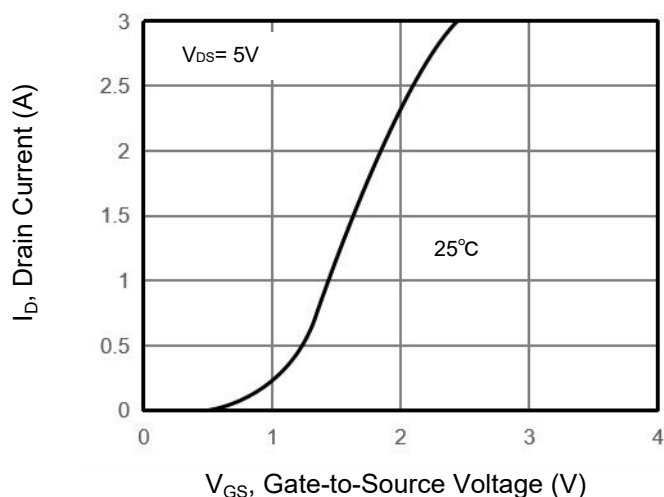


## NMOS Typical Characteristics $T_J = 25^\circ\text{C}$ , unless otherwise noted

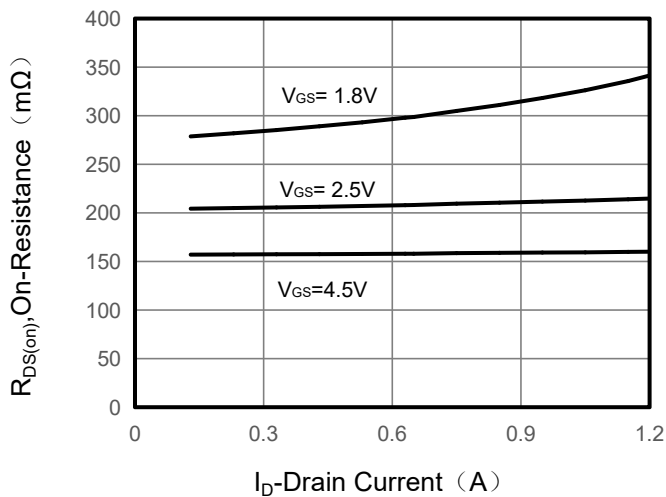
**Figure 1. Output Characteristics**



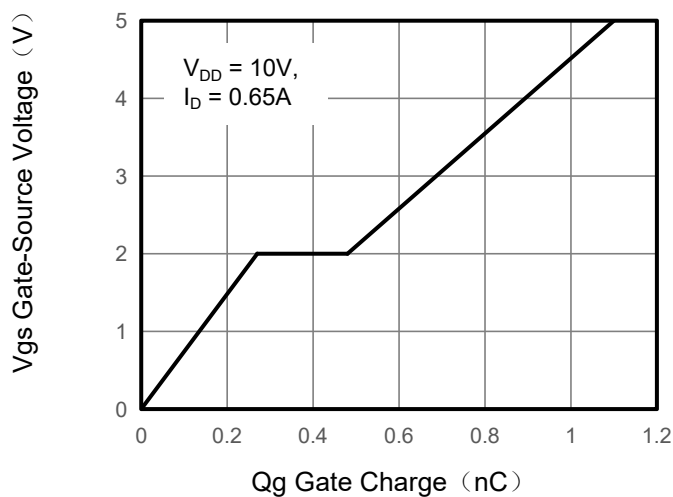
**Figure 2. Transfer Characteristics**



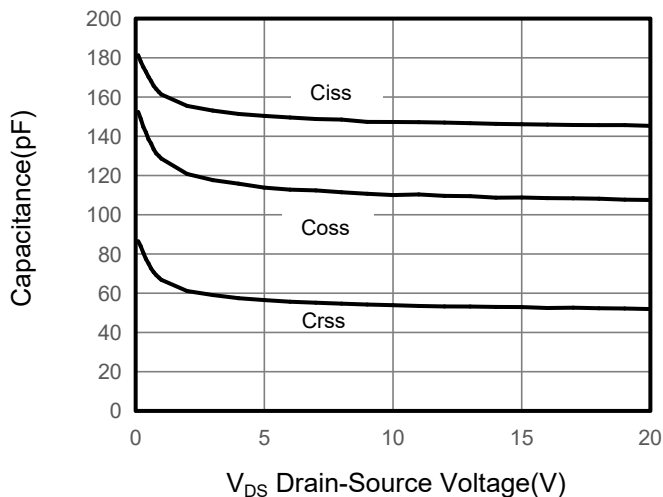
**Figure 3. Drain Source On Resistance**



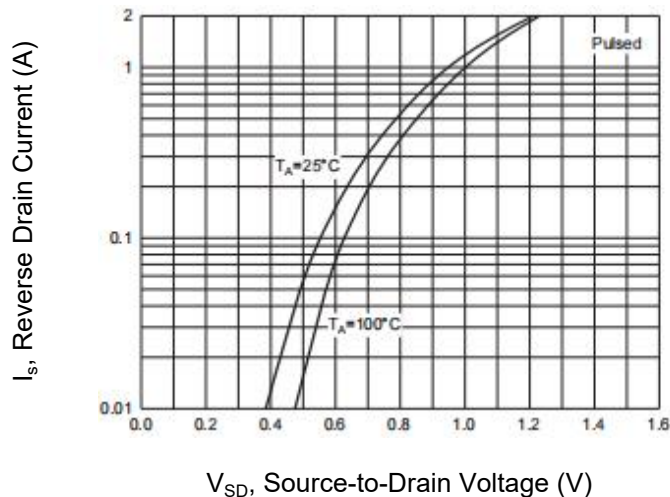
**Figure 4. Gate Charge**



**Figure 5. Capacitance**



**Figure 6. Source-Drain Diode Forward**



## NMOS Typical Characteristics $T_J = 25^\circ\text{C}$ , unless otherwise noted

Figure 7. Drain-Source On-Resistance

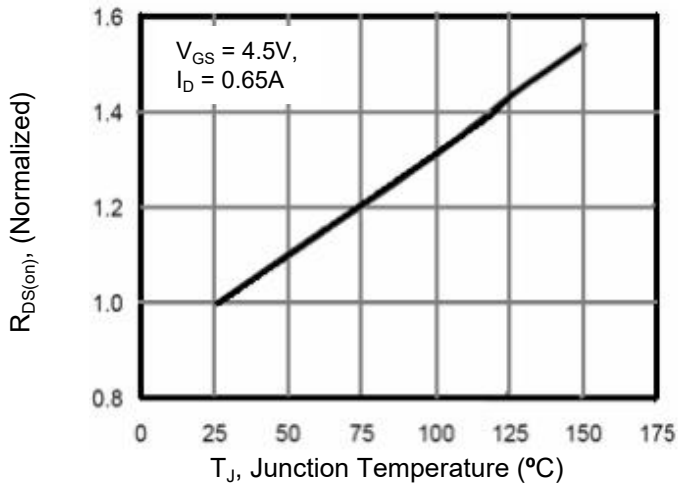


Figure 8. Safe Operation Area

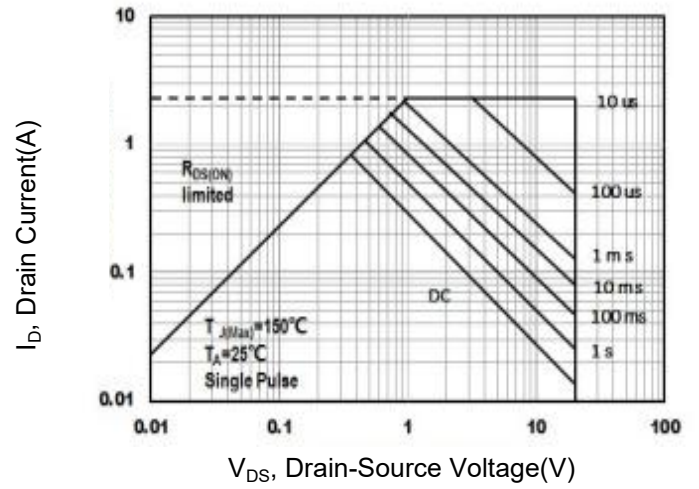
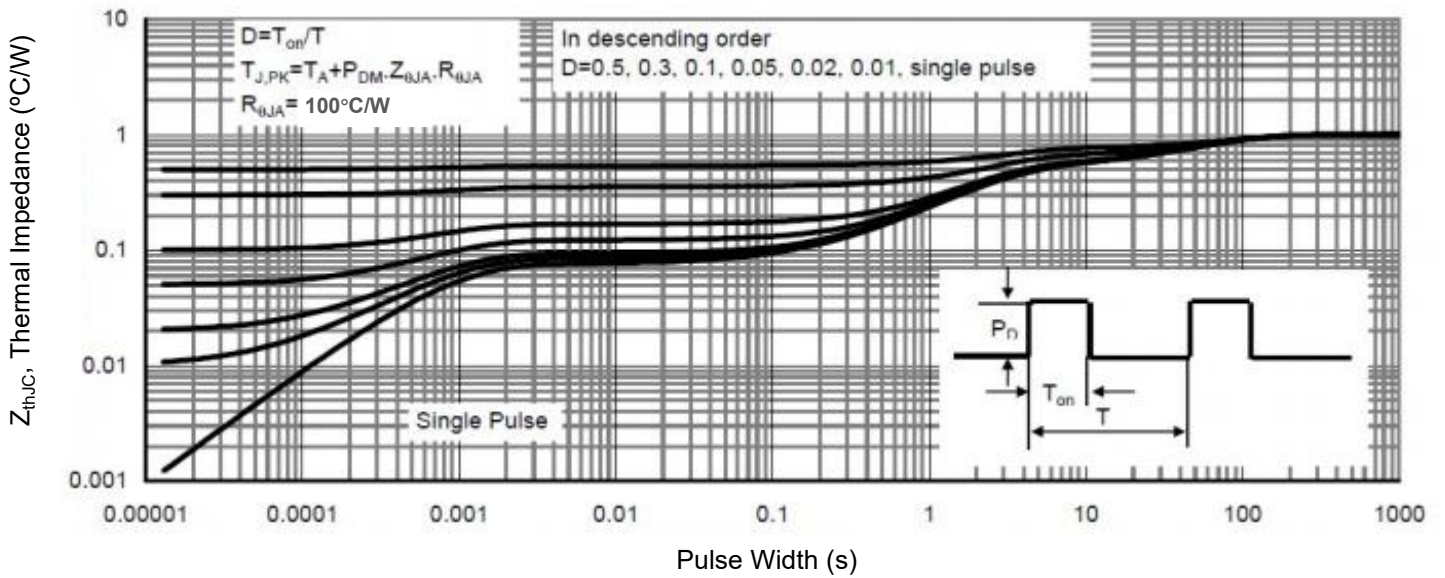


Figure 9. Normalized Maximum Transient Thermal Impedance

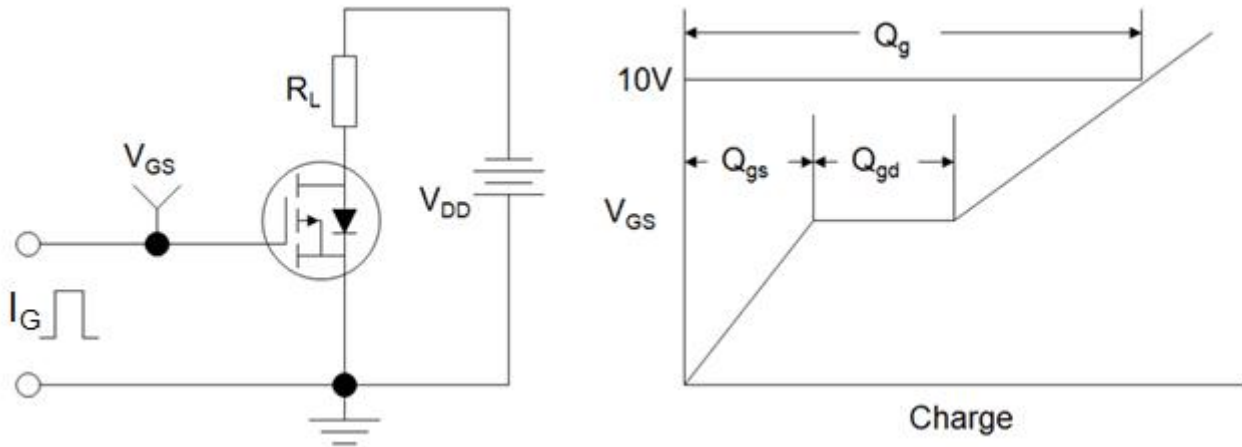


PMOS Specifications $T_J = 25^\circ\text{C}$ , unless otherwise noted						
Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
<b>Static Parameters</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu A$	-20	--	--	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -20V, V_{GS} = 0V$	--	--	-1	$\mu A$
Gate-Source Leakage	$I_{GSS}$	$V_{GS} = \pm 10V$	--	--	$\pm 10$	$\mu A$
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\mu A$	-0.35	-0.55	-0.8	V
Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = -4.5V, I_D = -0.5A$	--	380	460	m $\Omega$
		$V_{GS} = -2.5V, I_D = -0.5A$	--	480	580	
		$V_{GS} = -1.8V, I_D = -0.5A$	--	630	760	
Forward Transconductance	$g_{FS}$	$V_{DS} = -5V, I_D = -0.5A$	--	1.3	--	S
<b>Dynamic Parameters</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V,$ $V_{DS} = -10V,$ $f = 1.0MHz$	--	177	--	pF
Output Capacitance	$C_{oss}$		--	109	--	
Reverse Transfer Capacitance	$C_{rss}$		--	51	--	
Total Gate Charge	$Q_g$	$V_{DD} = -10V,$ $I_D = -0.5A,$ $V_{GS} = -4.5V$	--	1.22	--	nC
Gate-Source Charge	$Q_{gs}$		--	0.36	--	
Gate-Drain Charge	$Q_{gd}$		--	0.26	--	
Turn-on Delay Time	$t_{d(on)}$	$V_{DD} = -10V,$ $I_D = -0.5A,$ $R_G = 3\Omega$	--	18	--	ns
Turn-on Rise Time	$t_r$		--	4.5	--	
Turn-off Delay Time	$t_{d(off)}$		--	23	--	
Turn-off Fall Time	$t_f$		--	15	--	
<b>Drain-Source Body Diode Characteristics</b>						
Continuous Body Diode Current	$I_S$	$T_C = 25^\circ\text{C}$	--	--	-1.1	A
Body Diode Voltage	$V_{SD}$	$T_J = 25^\circ\text{C}, I_{SD} = -0.5A, V_{GS} = 0V$	--	--	-1.2	V
Reverse Recovery Charge	$Q_{rr}$	$I_F = -0.5A, V_{GS} = 0V$ $di/dt = -20A/\mu s$	--	0.95	--	nC
Reverse Recovery Time	$T_{rr}$		--	24	--	ns

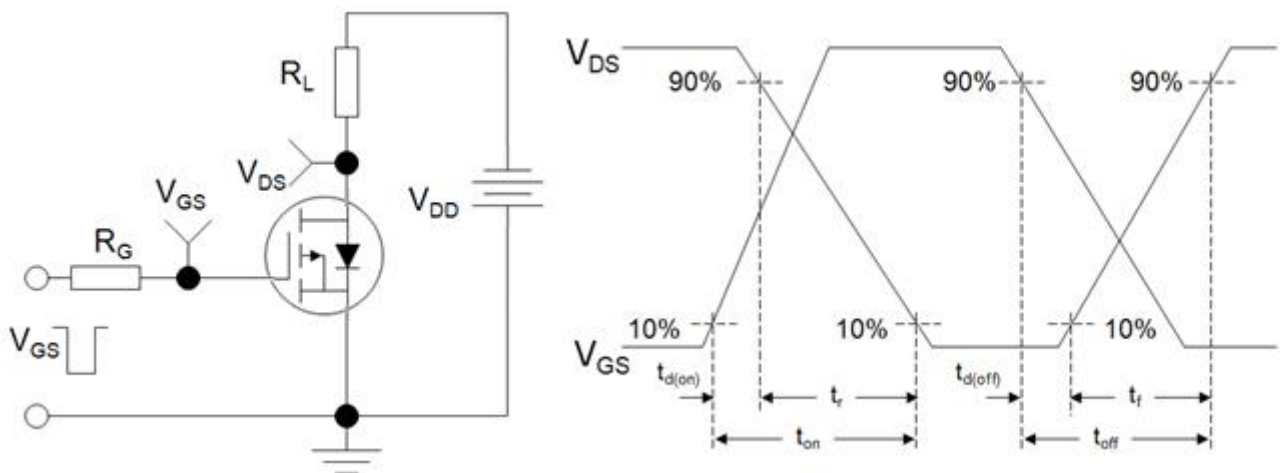
### Notes

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. EAS condition :  $T_J = 25^\circ\text{C}, V_{DD} = -20V, V_{GS} = -10V, L = 0.5mH, R_G = 25\Omega$
3. Identical low side and high side switch with identical  $R_G$

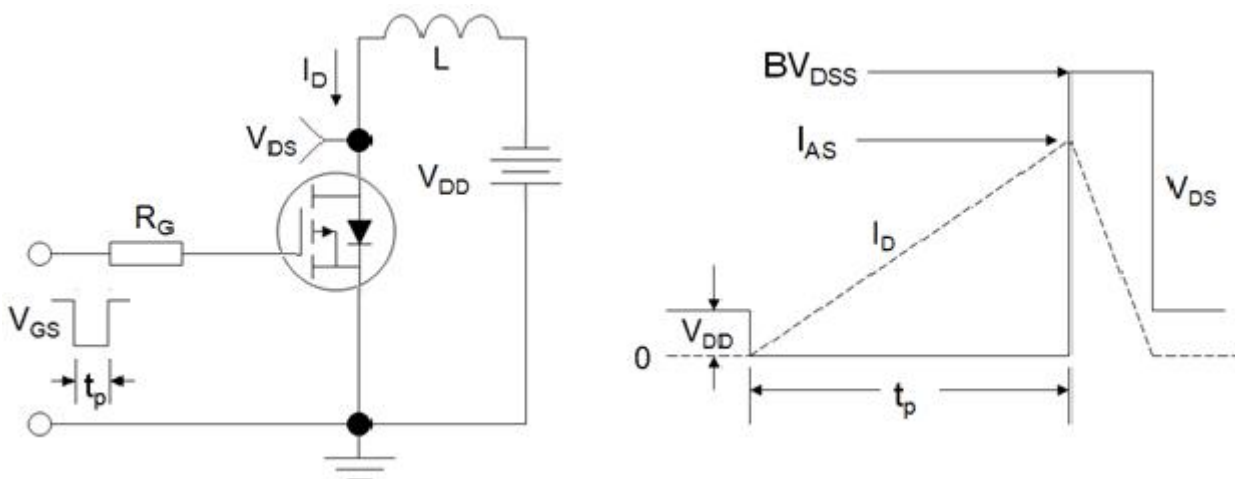
### Gate Charge Test Circuit



### Switch Time Test Circuit



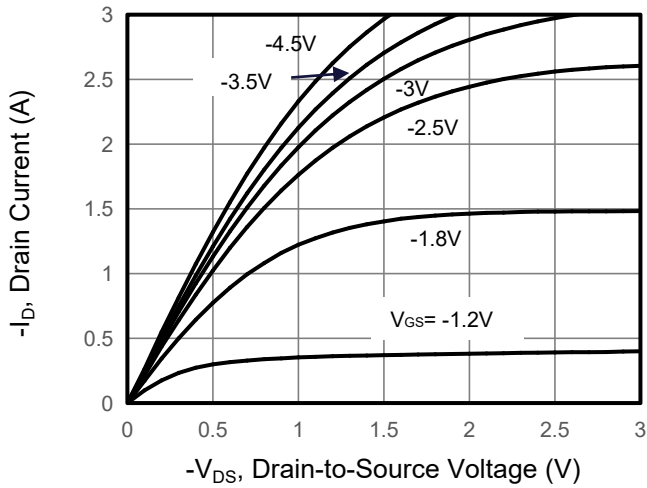
### EAS Test Circuit



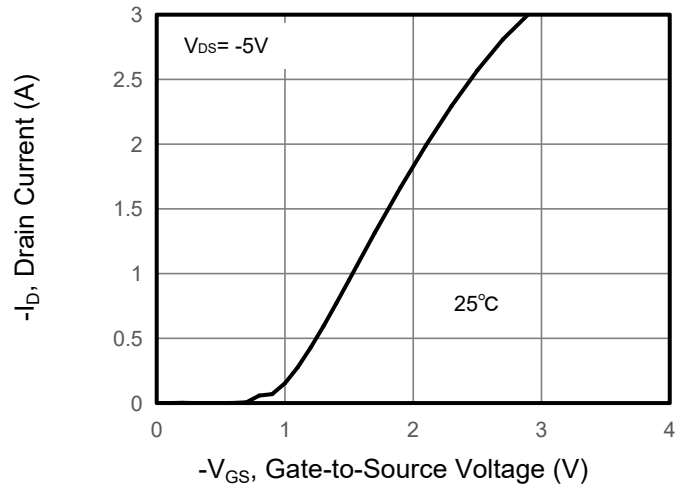


## PMOS Typical Characteristics $T_J = 25^\circ\text{C}$ , unless otherwise noted

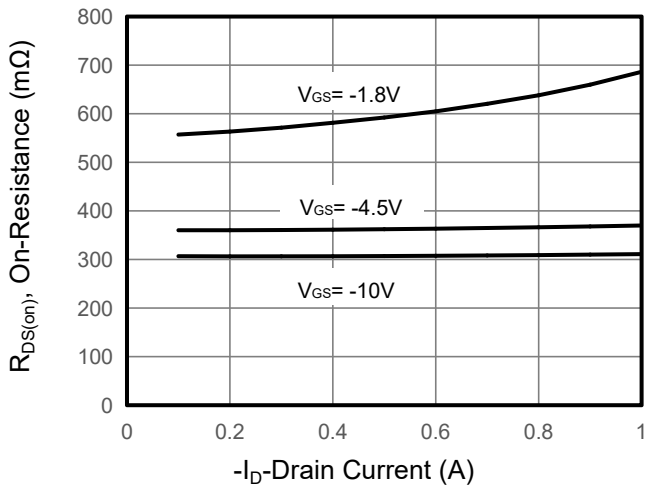
**Figure 1. Output Characteristics**



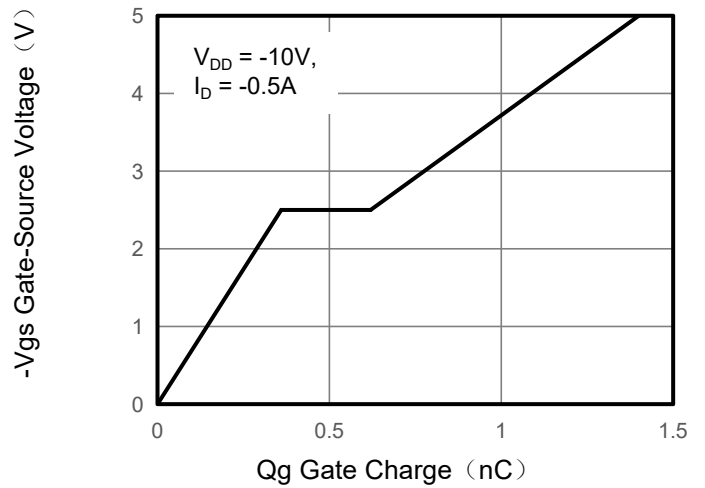
**Figure 2. Transfer Characteristics**



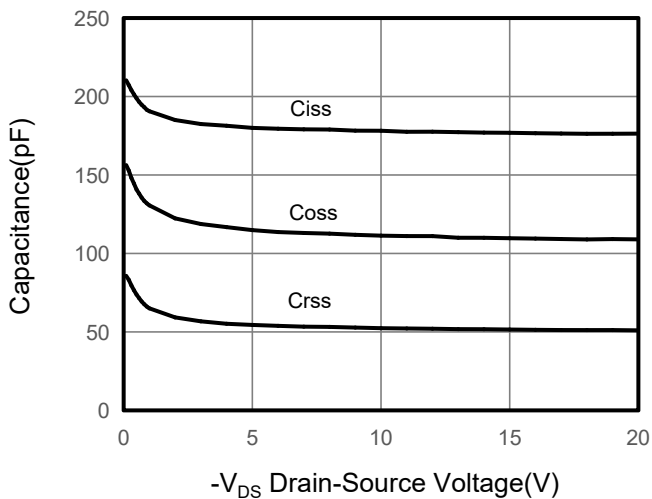
**Figure 3. Drain Source On Resistance**



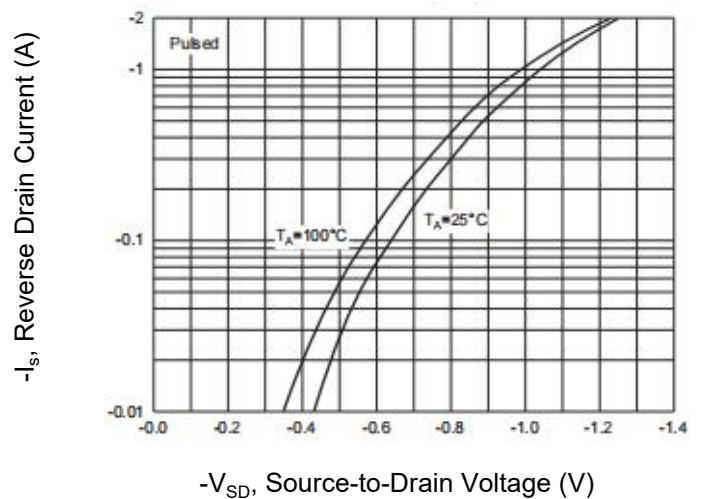
**Figure 4. Gate Charge**



**Figure 5. Capacitance**



**Figure 6. Source-Drain Diode Forward**





## PMOS Typical Characteristics $T_J = 25^\circ\text{C}$ , unless otherwise noted

Figure 7. Drain-Source On-Resistance

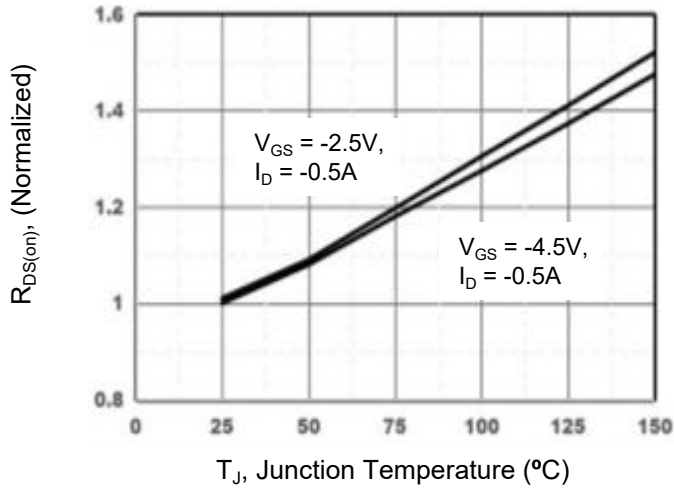


Figure 10. Safe Operation Area

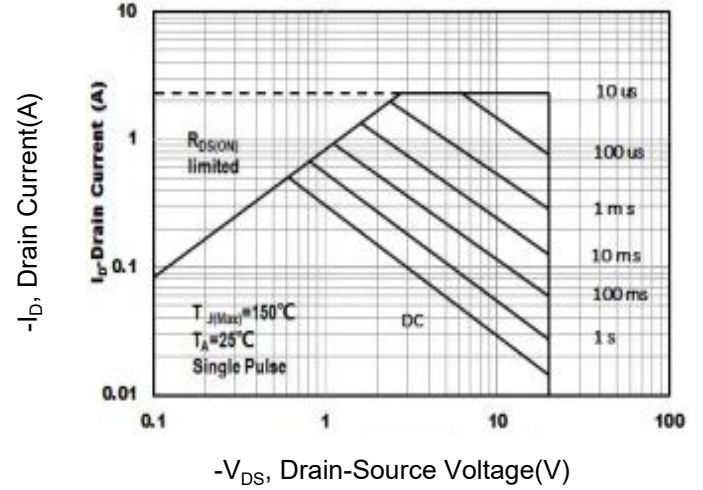
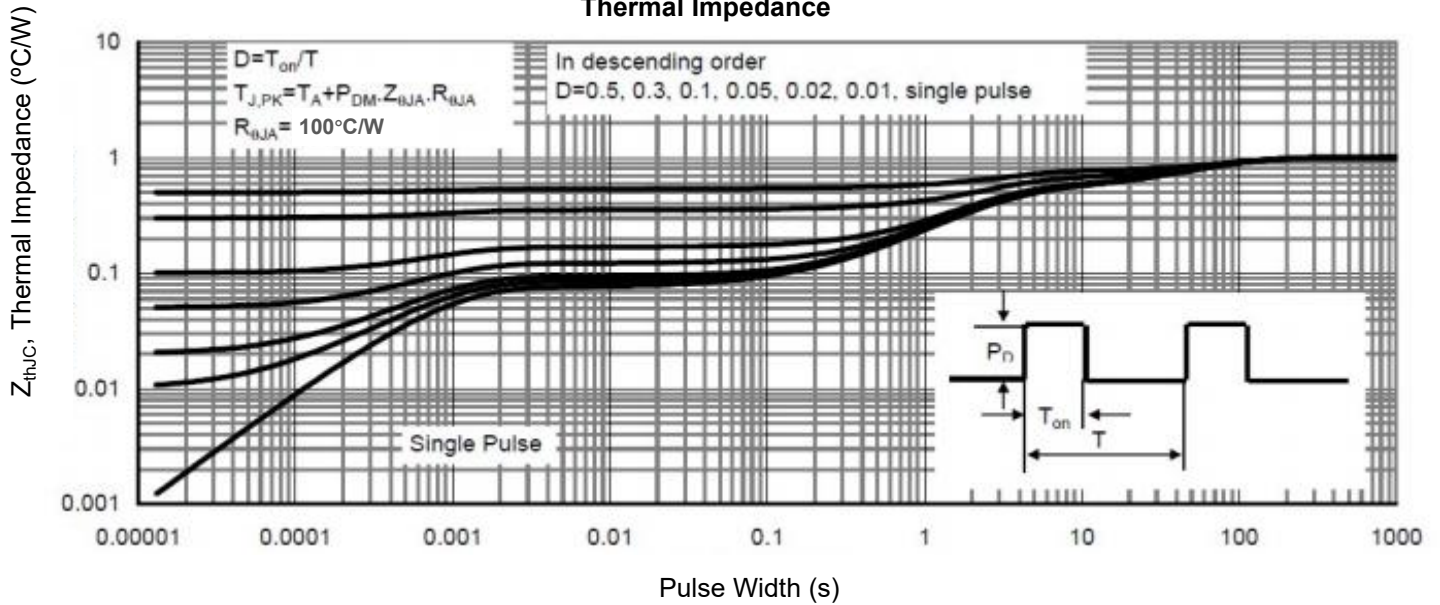
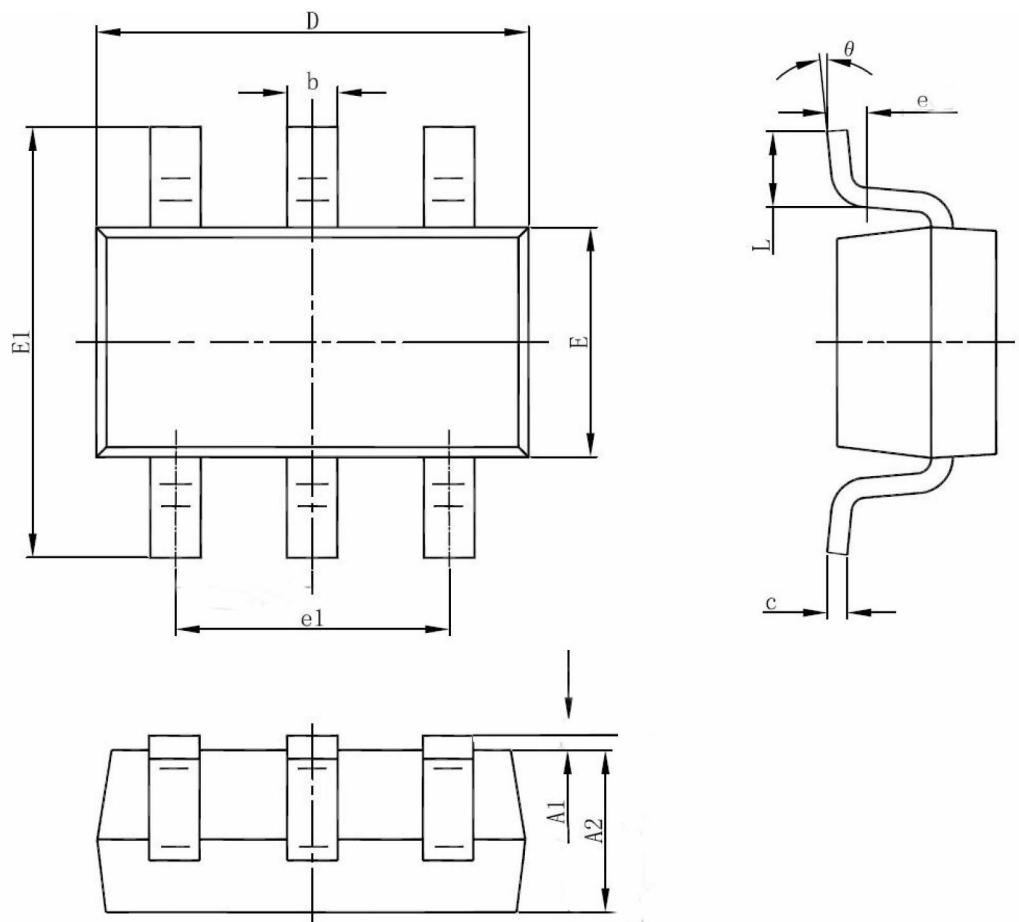


Figure 9. Normalized Maximum Transient Thermal Impedance



## SOT-23-6L Package Information



DIM	MIN	NOM	MAX
A1	0.00	-	0.10
A2	1.00	1.10	1.20
b	0.30	0.40	0.50
c	0.10	0.15	0.20
D	2.80	2.90	3.00
E	1.50	1.60	1.70
E1	2.60	2.80	3.00
e	0.2GAUGE PLANE		
e1	-	1.90	-
L	0.30	0.45	0.60
$\theta$	0°	-	8°
All Dimensions in mm			